

L Number	Hits	Search Text	DB	Time stamp
-	128	"10423"	USPAT; US-PGPUB	2004/02/06 12:24
-	1	"10423177"	USPAT; US-PGPUB	2003/12/10 16:34
-	1	6646347.pn.	USPAT; US-PGPUB	2004/01/30 14:56
-	121567	electrostatic	USPAT; US-PGPUB	2004/01/30 14:56
-	7400	electrostatic adj discharge	USPAT; US-PGPUB	2004/01/30 14:57
-	2029	(electrostatic adj discharge) and diode and transistor	USPAT; US-PGPUB	2004/01/30 14:57
-	474	((electrostatic adj discharge) and diode and transistor) and testing	USPAT; US-PGPUB	2004/01/30 14:57
-	2794	testing same diode	USPAT; US-PGPUB	2004/01/30 14:58
-	62	((electrostatic adj discharge) and diode and transistor) and testing) and testing same diode	USPAT; US-PGPUB	2004/01/30 14:58
-	9895	((electrostatic adj discharge) or ESD)	USPAT; US-PGPUB	2004/02/04 11:41
-	310	((electrostatic adj discharge) or ESD)) and ((first and second) adj diode)	USPAT; US-PGPUB	2004/02/04 11:41
-	302	((electrostatic adj discharge) or ESD)) and ((first and second) adj diode)) and circuit	USPAT; US-PGPUB	2004/02/04 11:42
-	260	((electrostatic adj discharge) or ESD)) and ((first and second) adj diode)) and circuit) and transistor	USPAT; US-PGPUB	2004/02/04 11:42
-	349709	((electrostatic adj discharge) or ESD)) and ((first and second) adj diode)) and circuit) and transistor) and test or testing	USPAT; US-PGPUB	2004/02/04 11:42
-	84	((electrostatic adj discharge) or ESD)) and ((first and second) adj diode)) and circuit) and transistor) and (test or testing)	USPAT; US-PGPUB	2004/02/04 11:42
-	1676	257/355	USPAT; US-PGPUB	2004/02/04 13:08
-	206	257/355 and (zener adj diode)	USPAT; US-PGPUB	2004/02/04 13:09
-	177	(257/355 and (zener adj diode)) and transistor	USPAT; US-PGPUB	2004/02/04 13:30
-	1	"4975798".PN.	USPAT	2004/02/04 13:26
-	1	"5151767".PN.	USPAT	2004/02/04 13:26
-	1	"5289028".PN.	USPAT	2004/02/04 13:26
-	1	"5362980".PN.	USPAT	2004/02/04 13:26
-	1	"5530271".PN.	USPAT	2004/02/04 13:26
-	1	"5557127".PN.	USPAT	2004/02/04 13:27
-	1	"5883402".PN.	USPAT	2004/02/04 13:27
-	1	"5903025".PN.	USPAT	2004/02/04 13:27
-	1	"5959345".PN.	USPAT	2004/02/04 13:27
-	1	"6091086".PN.	USPAT	2004/02/04 13:27
-	929	257/355 and ((electrostatic adj discharge) or ESD)	USPAT; US-PGPUB	2004/02/04 13:31
-	600	(257/355 and ((electrostatic adj discharge) or ESD)) and diode	USPAT; US-PGPUB	2004/02/04 13:31
-	552	((257/355 and ((electrostatic adj discharge) or ESD)) and diode) and transistor	USPAT; US-PGPUB	2004/02/04 13:31

-	150	((257/355 and ((electrostatic adj discharge) or ESD)) and diode) and transistor) and (test or testing)	USPAT; US-PGPUB	2004/02/04 13:57
-	1702	257/780	USPAT; US-PGPUB	2004/02/04 13:57
-	196	257/780 and (bonding adj pad) and wire	USPAT; US-PGPUB	2004/02/04 13:58
-	196	257/780 and ((bonding adj pad) and wire)	USPAT; US-PGPUB	2004/02/04 13:58
-	10	(257/780 and ((bonding adj pad) and wire)) and ((first and second) adj (bonding adj pad))	USPAT; US-PGPUB	2004/02/04 15:01
-	639	257/673	USPAT; US-PGPUB	2004/02/04 15:01
-	69	257/673 and chip and wire and (bonding adj pad)	USPAT; US-PGPUB	2004/02/04 15:14
-	922	257/360	USPAT; US-PGPUB	2004/02/04 15:14
-	514	257/360 and electrostatic adj discharge	USPAT; US-PGPUB	2004/02/04 15:14
-	323	(257/360 and electrostatic adj discharge) and diode	USPAT; US-PGPUB	2004/02/04 15:14
-	312	((257/360 and electrostatic adj discharge) and diode) and transistor	USPAT; US-PGPUB	2004/02/04 15:14
-	45	((257/360 and electrostatic adj discharge) and diode) and transistor) and bonding adj pad	USPAT; US-PGPUB	2004/02/04 15:15
-	375	257/363	USPAT; US-PGPUB	2004/02/04 15:15
-	185	257/363 and electrostatic adj discharge	USPAT; US-PGPUB	2004/02/04 15:16
-	136	(257/363 and electrostatic adj discharge) and diode	USPAT; US-PGPUB	2004/02/04 15:16
-	131	((257/363 and electrostatic adj discharge) and diode) and transistor	USPAT; US-PGPUB	2004/02/04 15:16
-	1	5853905.pn.	USPAT; US-PGPUB	2004/02/06 12:24